

## SEU effects in deep submicron processes

*Thursday 9 June 2011 09:15 (1h 45m)*

As feature sizes of modern electronics continue to shrink, the study and mitigation of radiation effects in electronics has become an important part of high-reliability computing. In this talk trends in memory devices, field-programmable gate arrays and microprocessors that cause data corruption or computational failures will be presented. Mitigation methods that attempt to suppress the affect of radiation-induced failures will also be discussed.

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